

● General Description

This silicon carbide Power MOSFET device has been developed using ZMJ’s advanced 2nd generation SiC MOSFET technology. The device features a very low $R_{DS(on)}$ over the entire temperature range combined with low capacitances and very high switching operations. It improves application performance in frequency, energy efficiency, system size and weight reduction.

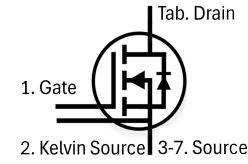
● Features

- High Blocking Voltage
- High Speed Switching With Low Capacitances
- Low $R_{DS(ON)}$ to Minimize Conductive Loss
- Low Gate Charge For Fast Switching
- Low Thermal Resistance
- 100% Avalanche Tested
- AEC-Q101 Qualified

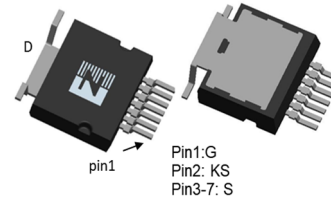
● Application

- Motor Drives
- On Board Charger
- DC-DC
- Auxiliary Drives

● Product Summary



$V_{DS} = 1200V$
 $R_{DS(ON)} = 49m\Omega$
 $I_D = 37A$



T2PAK



● Ordering Information:

Part NO.	ZMCA060R120T2
Marking	ZMC060R120
Packing Information	REEL TAPE
Basic Ordering Unit (pcs)	700

● Absolute Maximum Ratings ($T_C=25^\circ C$)

Parameter	Symbol	Conditions	Value	Unit
Drain-Source Voltage	V_{DS}		1200	V
Gate-Source Voltage	V_{GS}	Transient Voltage	-10V/25V	V
	V_{GS}	Static Voltage	-10V/24V	V
Recommended Turn On Gate Voltage	$V_{GS(on)}$		15 to 18V	V
Recommended Turn Off Gate Voltage	$V_{GS(off)}$		-4V to 0V	V
Continuous Drain Current	I_D	$T_C=25^\circ C$	37	A
	I_D	$T_C=75^\circ C$	30	A
	I_D	$T_C=100^\circ C$	26	A

1200V N-Channel SiC MOSFET

Pulsed Drain Current ^①	I_{DM}	Pulsed; $t_p \leq 10 \mu s$; $T_{mb} = 25^\circ C$;	148	A
Total Power Dissipation	P_D	$T_C = 25^\circ C$	224	W
Total Power Dissipation	P_D	$T_A = 25^\circ C$	3.0	W
Operating Junction Temperature	T_J		-55 to +175	$^\circ C$
Storage Temperature	T_{STG}		-55 to +175	$^\circ C$
Single Pulse Avalanche Energy	E_{AS}	$L=0.5mH, V_{GS}=18V, R_g=25\Omega$	361	mJ
ESD Level (HBM)			Class2	

• Thermal Resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance, Junction - Case	R_{thJC}	-	-	0.67	$^\circ C/W$
Thermal Resistance, Junction-Ambient	$R_{thJA\oplus}$	-	-	50	$^\circ C/W$
Soldering Temperature(total time<10s)	T_{sold}	-	-	260	$^\circ C$

• Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	1200	-	-	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 5mA$	2	2.9	4	V
Drain-Source Leakage Current	I_{DSS}	$V_{GS} = 0V, V_{DS} = 1200V$	-	-	10	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS} = -10V, V_{DS} = 0V$	-	-	-100	nA
		$V_{GS} = 25V, V_{DS} = 0V$	-	-	100	nA
Static Drain-Source On Resistance	$R_{DS(on)}$	$T_J = 25^\circ C, V_{GS} = 18V, I_D = 20A$	-	49	65	m Ω
		$T_J = 175^\circ C, V_{GS} = 18V, I_D = 20A$	-	98	-	m Ω
		$T_J = 25^\circ C, V_{GS} = 15V, I_D = 20A$	-	59	-	m Ω
Forward Transconductance	g_{fs}	$V_{DS} = 10V, I_{SD} = 20A$	-	8.5	-	S
Diode Forward Voltage	V_{FSD}	$V_{GS} = -4V, I_{SD} = 20A$	-	4.2	5	V

• Dynamic Characteristics

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input Capacitance	C_{iss}	$f = 100KHz, V_{DS} = 800V$	-	1538	-	pF
Output Capacitance	C_{oss}		-	62	-	
Reverse Transfer Capacitance	C_{rss}		-	3	-	
Output Charge	Q_{oss}	$f = 100KHz, V_{GS} = 0V, V_{DS} = 0V \text{ to } 800V$	-	89	-	nC
Coss Stored Energy	E_{oss}		-	23	-	μJ
Gate Resistance	R_g	$f = 1MHz$	-	1.5	-	Ω
Total Gate Charge	Q_g	$V_{DD} = 800V, I_D = 20A, V_{GS} = -4V/18V$	-	69	-	nC
Gate - Source Charge	Q_{gs}		-	19	-	
Gate - Drain Charge	Q_{gd}		-	28	-	

Turn-ON Delay Time	$t_{D(on)}$	$V_{GS}=-4V/18V, V_{DS}=800V,$ $R_G=10\Omega, I_D=20A,$ $L=505\mu H$	-	13	-	ns
Turn-ON Rise Time	t_r		-	3.4	-	ns
Turn-Off Delay Time	$t_{D(off)}$		-	36	-	ns
Turn-Off Fall Time	t_f		-	15	-	ns
Turn-On Energy	E_{on}		-	527	-	μJ
Turn-Off Energy	E_{off}		-	153	-	μJ
Reverse Recovery Time	t_{rr}	$V_{DD}=800V, di_S/dt =$ $600A/\mu s, I_S=20A$	-	25	-	ns
Reverse Recovery Peak Current	I_{rrm}		-	5.8	-	A
Reverse Recovery Charge	Q_{rr}		-	82	-	nC

● Characteristics Diagrams

Fig.1 Gate-Charge Characteristics

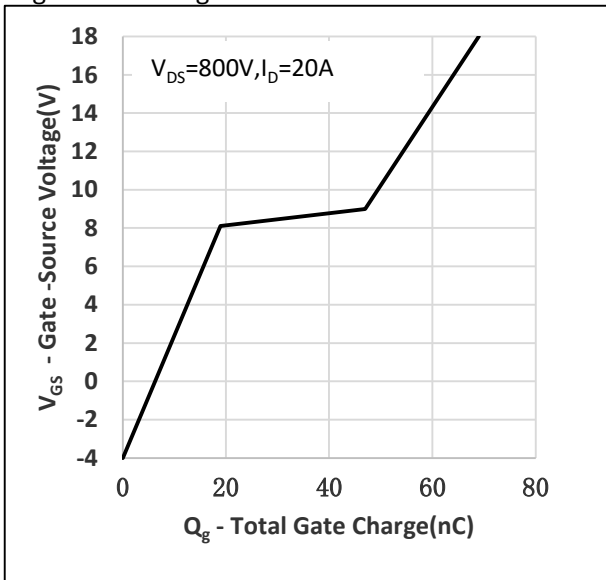


Fig.2 Capacitance Characteristics

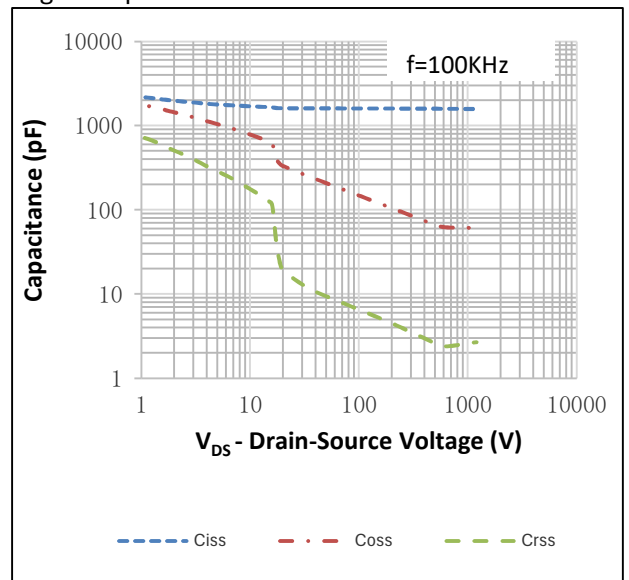


Fig.3 Power Dissipation

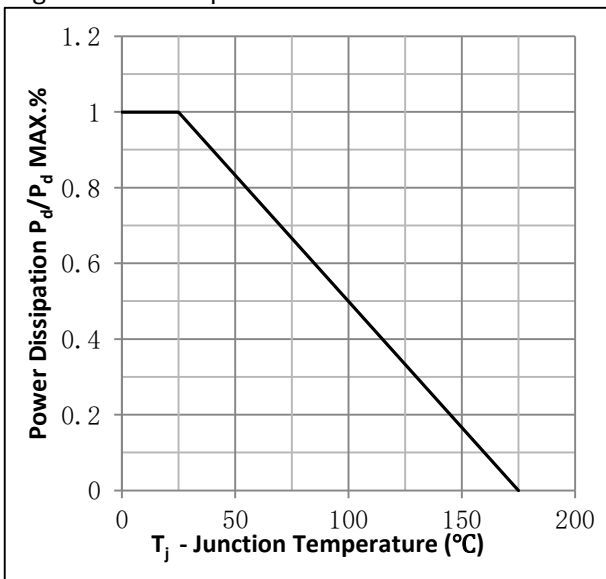


Fig.4 Typical Output Characteristics

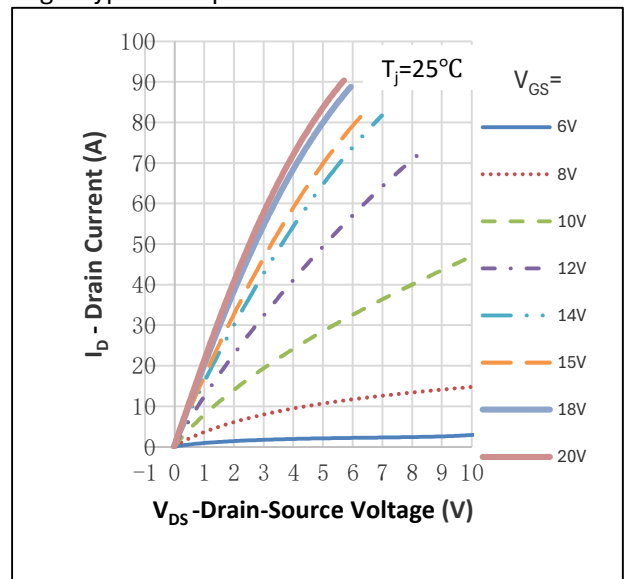


Fig.5 Threshold Voltage vs. Junction Temperature

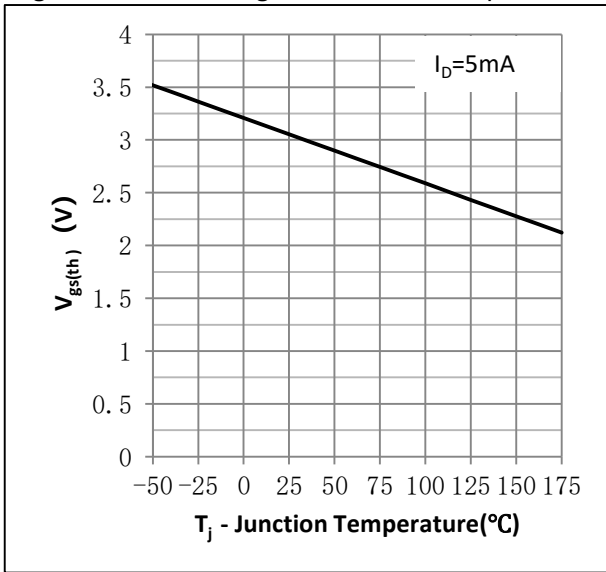


Fig.6 On-Resistance vs. Drain Current

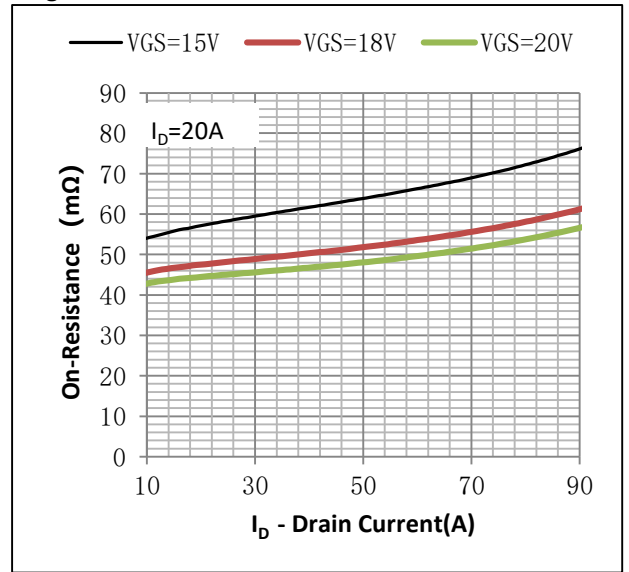


Fig.7 On-Resistance vs. Gate Source Voltage

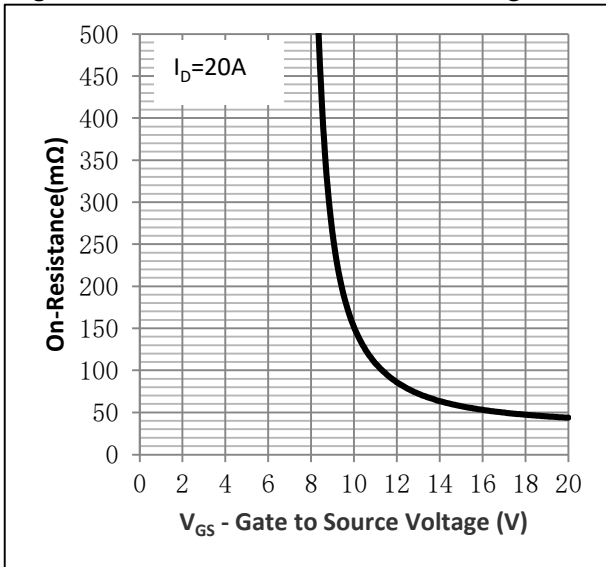


Fig.8 On-Resistance vs. Junction Temperature

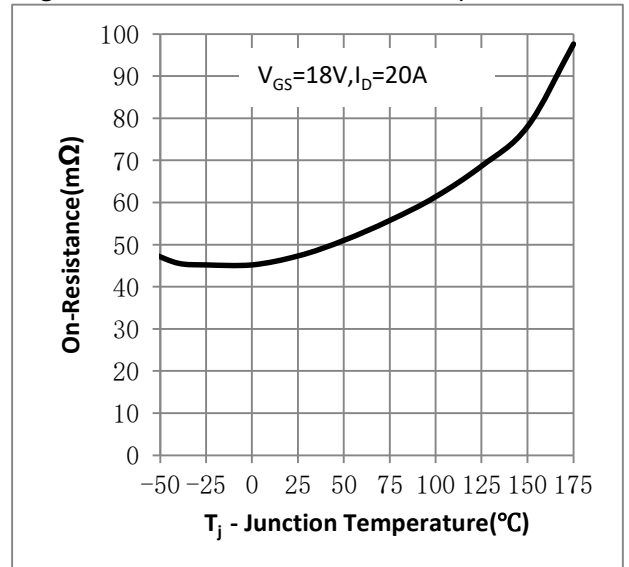


Figure 9. Diode Forward Voltage vs. Current

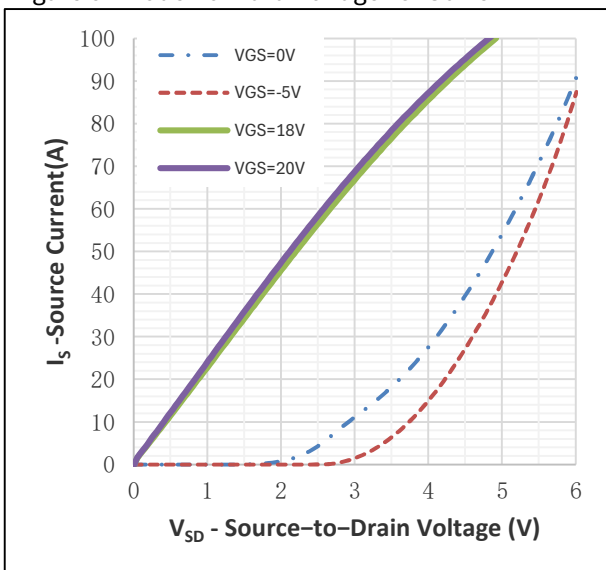


Figure 10. Transfer Characteristics

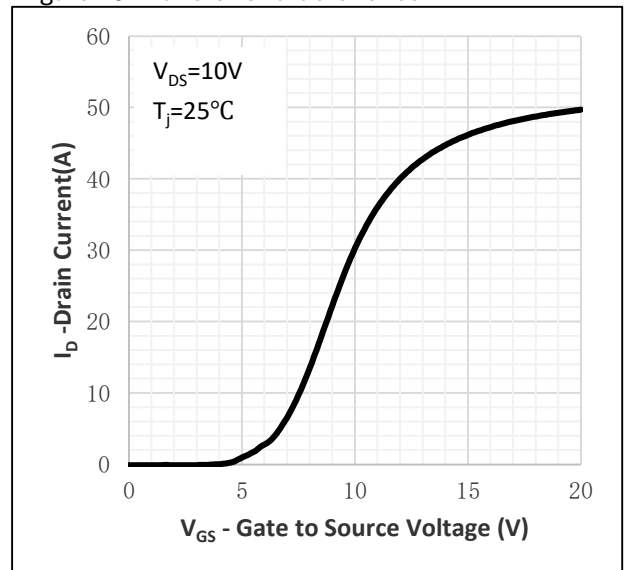


Fig.11 SOA Maximum Safe Operating Area

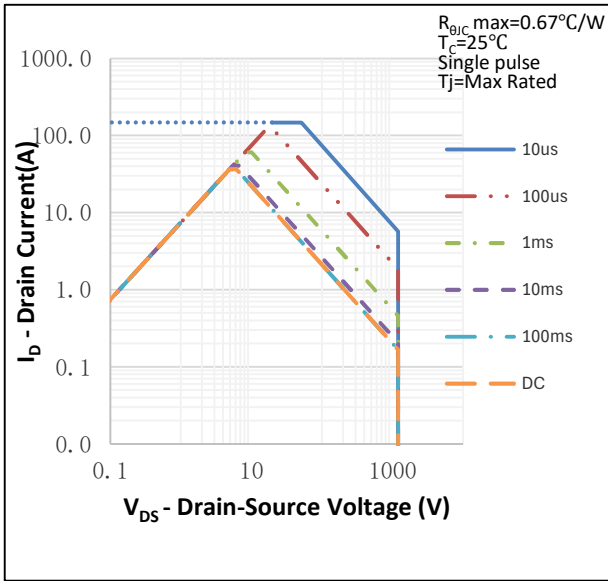


Fig.12 I_D vs. Junction Temperature②

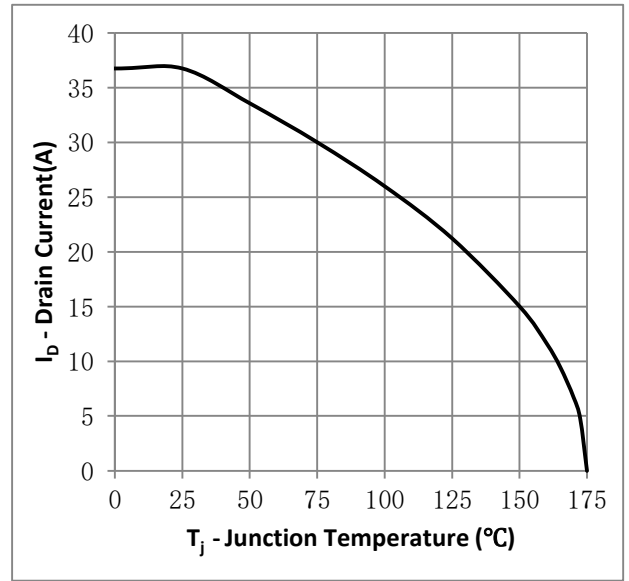


Fig.13 Output Capacitor Stored Energy

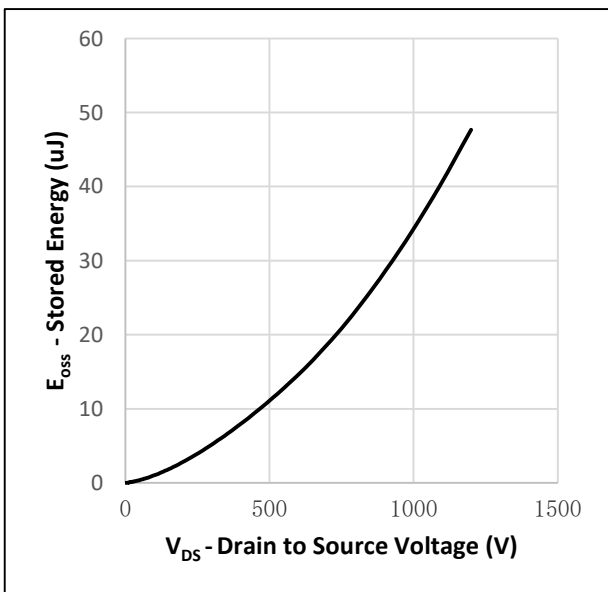
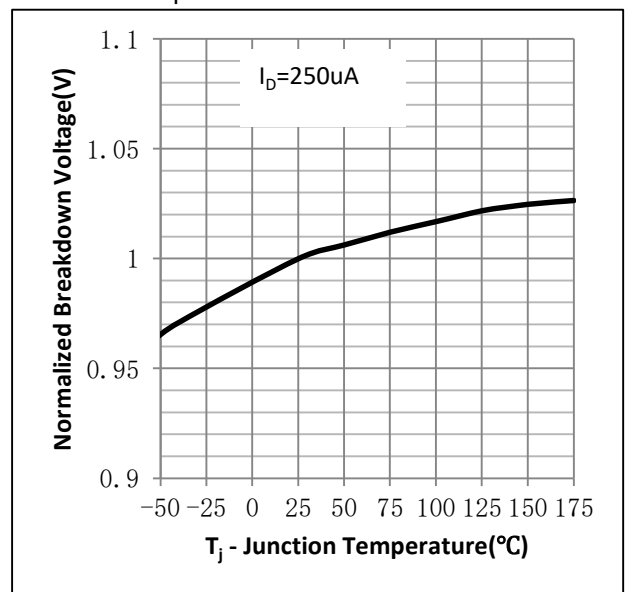
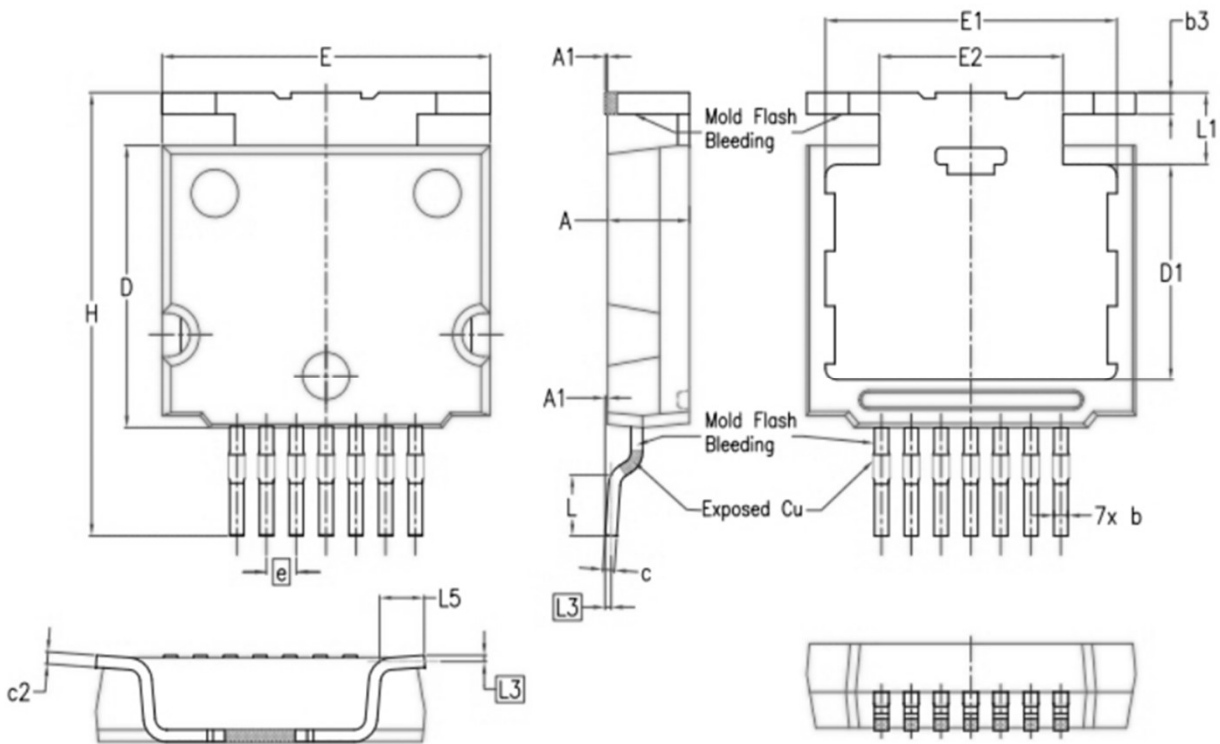


Fig.14 Normalized Breakdown Voltage vs. Junction Temperature



•T2PAK Package Outline



SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	3,40	3,50	3,60
A1	0,00	0,10	0,25
b	0,50	0,60	0,70
b3	0,80	0,90	1,00
c	0,40	0,50	0,60
c2	0,40	0,50	0,60
D	11,70	11,80	11,90
D1	8,80	9,00	9,10
E	13,90	14,00	14,10
E1	12,30	12,40	12,50
E2	7,75	7,80	7,85
e	1,27 BSC		
H	18,00	18,50	19,00
L	2,30	2,50	2,75
L1	—	3,05	—
L3	—	0,26	—
L5	1,70	1,90	2,15



Note:

- ① The value of $R\theta JA$ is measured with the device in a still environment with $T_A=25^\circ C$
- ② Practically the current will be limited by PCB, thermal design and operating temperature. $V_{GS}=18V$.

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Revision History:

Version	Date	Change
A	2024/11/27	New